Application/Control No.	Applicant(s)/Patent under Reexamination
10/784,954	OIKAWA ET AL.
Examiner	Art Unit
Patrick H. Mackey	3651

SEARCHED							
Class	Subclass	Date	Examiner				
271	208						
270	58.08	9/30/2004	PHM				
Updated	Search	2/25/2005	РНМ				
Above	Updated	11/7/2005	РНМ				
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